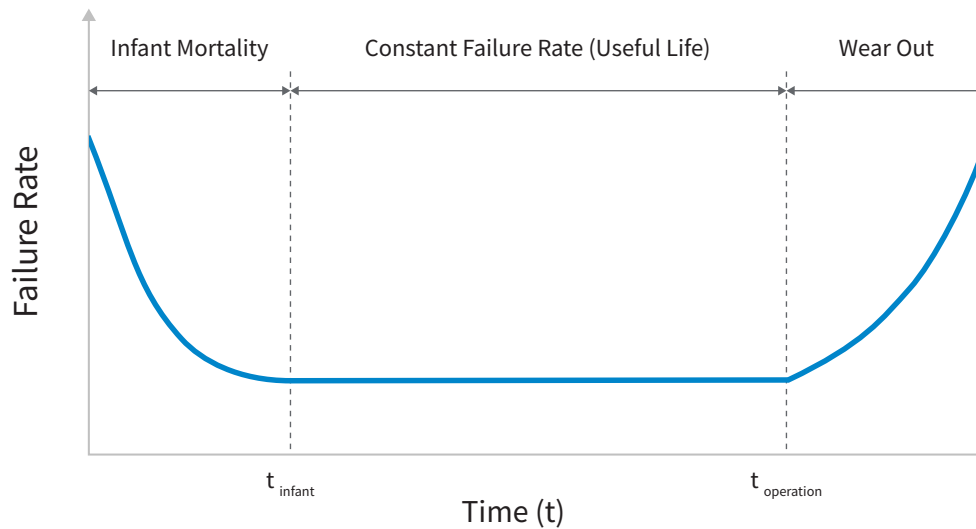


Burn-In for Gate Drivers

- Reduces total cost of ownership and streamlines production
- Eliminates challenges posed by in-house solutions and removes the need for specialized subcontractors
- Reduces failure rate by up to 15 PPM
- Extended warranty available with burn-in

Enhanced Field Reliability

Power Integrations' gate driver products for demanding applications with >100,000 hour operating lifetime. Burn-in testing eliminates infant mortality, improving system reliability and reducing maintenance challenges.

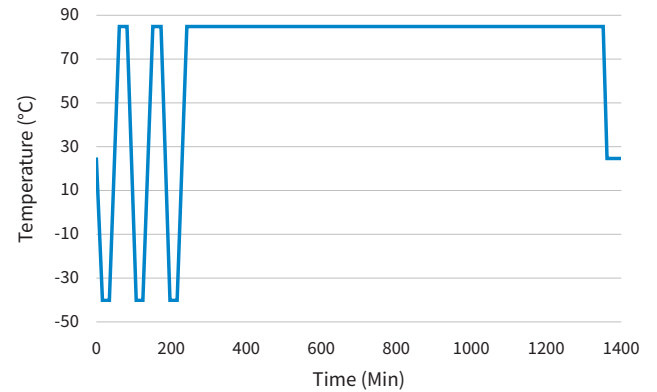


Applications

- Mission-critical and high reliability systems
- Transportation
- Electrical generation and transmission

Burn-In Process

- 100% production test
- Burn-in profile
 - 23-hour burn-in cycle
 - Controlled oven profile
 - Three cycles -40 °C to +85 °C (258 minutes)
 - 1092-minute dwell-time at 85 °C
 - 30-minute off-time at 25 °C
- Customer-specific burn-in profile on request



Burn-In – In-Line Process Flow

